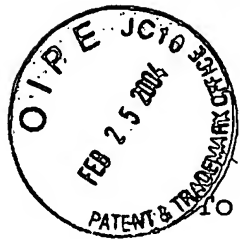


TSMC-02-1367



February 18, 2004

To: Commissioner for Patents
P.O.Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/731,346 12/09/03 |

Fang-Cheng Chen et al.

METHOD OF FORMING A SEMICONDUCTOR
DEVICE WITH A HIGH DIELECTRIC CON-
STANT MATERIAL AND AN OFFSET SPACER
| _____ |

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.

The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on February 23, 2004.

Stephen B. Ackerman, Reg.# 37761

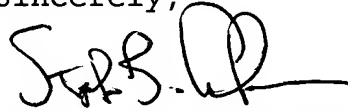
Signature/Date

Stephen B. Ackerman 2/23/04

The following two U.S. Patents describe the use of high k materials for use as sidewall spacers as well as for a component of a composite gate insulator layer:

- 1) U.S. Patent 6,258,675 to Gardner et al., "High K Gate Electrode."
- 2) U.S. Patent 5,904,517 to Gardner et al., "Ultra Thin High K Spacer Material for Use in Transistor Fabrication."

Sincerely,

A handwritten signature in black ink, appearing to read "S.B. Ackerman", with a stylized flourish at the end.

Stephen B. Ackerman,
Reg. No. 37761

Form PTO-1449

Docket Number (Specimen)

Application Number

TSMC-02-1367

10/731,346

Applicant

Fang-Cheng Chen et al.

Filing Date

12/09/03

Group Art Unit

INFORMATION DISCLOSURE CITATION
IN AN APPLICATION

(Use several sheets if necessary)

U. S. PATENT DOCUMENTS

EXAMINER PATENT INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	ALSO DATE IF APPROPRIATE
	6258675	7/10/01	Gardner et al.	438	287	12/18/97
	5904517	5/18/99	Gardner et al.	438	197	7/8/98

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.